

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-190001	Application No. New Application
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Mitsuaki Osame et al.	
		Filing Date December 11, 2003	Group Art Unit 2818

U.S. Patent Documents

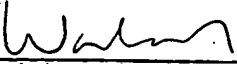
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
MW	AA	6,275,210	08/14/2001	Mackawa	345	98	11/12/1998
	AB						
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	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
MW	AL	11-184432	07/09/1999	JAPAN			ABS	
MW	AM	11-184440	07/09/1999	JAPAN			ABS	
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	Mitsuaki Osame et al.; U.S. Patent Application (serial number pending); filed December 1, 2003; Data Latch Circuit and Electronic Device
	AR	
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Examiner Signature 	Date Considered 10/29/04
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-190001	Application No. 10/732,830
	Applicant Mitsuaki Osame et al.		
	Filing Date December 11, 2003	Group Art Unit 2816	

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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							Yes	No
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MRW	AR	International Preliminary Examination Report (Application No. PCT/JP03/16028), April 30, 2004, Partial Translation, 4 pages.
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Examiner Signature <i>Wondan</i>	Date Considered 10/25/04
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	